



IFW/1742

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re the Application of: **Seiki TAKAHASHI**

Group Art Unit: **1742**

Serial No.: **10/510,639**

Examiner: **Not yet assigned**

Filed: **March 23, 2005**

Confirmation No.: **1901**

For: **NONDESTRUCTIVE INSPECTION METHOD OF GRAIN-  
BOUNDARY ATTACK OF CHROMIUM-CONTAINING NICKEL-  
BASED ALLOY AND INSPECTION APPARATUS FOR USE  
THEREIN**

Attorney Docket Number: **042779**

Customer Number: **38834**

**INFORMATION DISCLOSURE STATEMENT**  
**PURSUANT TO 37 C.F.R. §1.97(b)**

Commissioner for Patents  
P. O. Box 1450  
Alexandria, VA 22313-1450

Date: July 7, 2005

Sir:

In compliance with 37 C.F.R. §1.56, Applicant directs the attention of the Patent and Trademark Office to the documents listed on the attached PTO/SB/08. This paper is being filed within the time periods set forth in 37 C.F.R. §1.97(b). A copy of each non-U.S. document is enclosed herewith. The cited nos. AA to AC are discussed in pages 1-2 of the specification.

The Information Disclosure Statement was filed previously with the PTO-1449 Form on October 8, 2004 without copies of the references. Therefore, the copies of the references are also enclosed herewith.

If there are any fees due in connection with the filing of this paper, please charge Deposit  
Account No. 50-2866.

Respectfully submitted,  
**WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP**



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SK/sg  
Enclosures: PTO/SB/08  
7 Documents

JUL 07 2005

Complete if Known

**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Application Number	10/510,639
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First Named Inventor	Seiki TAKAHASHI
Art Unit	1742
Examiner Name	Not yet assigned
Attorney Docket Number	042779

Sheet

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of

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**U.S. PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code <sup>2</sup> (if known)		
		US			
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**FOREIGN PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation <sup>6</sup>
		Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)			
	AA	JP	02-54501	B	11/21/1990	MITSUBISHI HEAVY IND. LTD.	Abstract
	AB	JP	07-6950	B	01/30/1995	HITACHI LTD.	Abstract
	AC	JP	04-218764	A	08/10/1992	HITACHI LTD.	Abstract

**NON PATENT LITERATURE DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation <sup>6</sup>
	AD	G.P. Airey et al., <i>Detecting Grain-Boundary Chromium Depletion in Inconel 600</i> , Journal of Metals, November 1981, pages 28-35.	

Examiner Signature

Date Considered

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>See Kind Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov), MPEP 901.04 or in the comment box of this document. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to indicate here if English language Translation is attached.